

DETAILED ACTION

Allowable Subject Matter

1. Claims 37, 39 and 41 are allowed.
Claims 38 and 40 have been canceled.

Examiner's Amendment

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
 - A. Claim 37, lines 3 and 4: Delete "shape is arranged" and insert --- "pattern having a plurality of stripes with a rectangular shape having a long side and a short side in a plan view, is arranged directly" ---.
 - B. Claim 37, line 8: Delete "plan view, the bonding pads are arranged in order and on a" and insert --- "the plan view, the bonding pads are arranged uniformly and in order along the" ---.
 - C. Claim 37, at the last line 9: Delete "metal." and insert ---"metal, wherein a width W at a top and interval D of a bottom of each of the second metals satisfy a relation:
$$W \leq D \leq 2W, \text{ and}$$

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in the plan view, an input buffer and an output buffer are formed below each of the plurality of bonding pads, each of the input buffer and the output buffer including a transistor, the input buffer receiving a first signal from the bonding pad and outputting the first signal to an internal circuit, the output buffer receiving a second signal from the internal circuit and outputting the second signal to the bonding pad.” ---.

D. Cancel claims 38 and 40.

Authorization for this examiner's amendment was given in a telephone interview with Bernard Codd on 11-5-09.

Reasons for Allowance

3. The following is an examiner's statement of reasons for allowance:

The references of record do not teach the limitations “each of the plurality of second metals has a linear pattern having a plurality of stripes with a rectangular shape having a long side and a short side in a plan view, is arranged directly under the first metal, and is connected with the first metal” and “the bonding pads are arranged uniformly and in order along the long side direction of the second metal, wherein a width W at a top and interval D of a bottom of each of the second metals satisfy a relation: $W \leq D \leq 2W$, and in the plan view, an input buffer and an output buffer are formed below each of the plurality of bonding pads” in a semiconductor device having a plurality of bonding pads including a first metal and a pattern and a profile defining a plurality of second metals there under.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Nitin Parekh whose telephone number is 571-272-1663. The examiner can normally be reached on 09:00AM-05:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Lynne Gurley can be reached on 571-272-1670. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAN or Public PAG. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAG system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

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/Nitin Parekh/

Primary Examiner, Art Unit 2811